BS EN 60749-40:2011

BSI Standards Publication

Semiconductor devices — Mechanical and climatic test methods

Part 40: Board level drop test method using a strain gauge

National foreword

This British Standard is the UK implementation of EN 60749-40:2011. It is identical to IEC 60749-40:2011.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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Amendments issued since publication

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English version

Semiconductor devices - Mechanical and climatic test methods - Part 40: Board level drop test method using a strain gauge
(IEC 60749-40:2011)

Dispositifs à semiconducteurs -
Méthodes d'essais mécaniques et climatiques -
Partie 40: Méthode d'essai de chute au niveau de la carte avec utilisation d'une jauge de contrainte
(CEI 60749-40:2011)

Halbleiterbauelemente -
Mechanische und klimatische Prüfverfahren -
Teil 40: Prüfverfahren zum Fall einer Leiterplatte unter Verwendung von Dehnungsmessstreifen
(IEC 60749-40:2011)

This European Standard was approved by CENELEC on 2011-08-17. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

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CENELEC
European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 47/2094/FDIS, future edition 1 of IEC 60749-40, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60749-40 on 2011-08-17.

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The following dates were fixed:

– latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2012-05-17
– latest date by which the national standards conflicting with the EN have to be withdrawn	(dow)	2014-08-17

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 60749-40:2011 was approved by CENELEC as a European Standard without any modification.